

# Search Notes



Application/Control No.

10/727,540

Examiner

Shih-yung Hsieh

Applicant(s)/Patent under  
Reexamination

CHEN, TEDDY

Art Unit

2837

## SEARCHED

Class	Subclass	Date	Examiner
84	279		
	278		
	280	4/18/05	SMH

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
84	279		
	278		
	280	4/18/05	SMH

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR